

**Search Notes**

Application/Control No.

10/722,441

Examiner

James D. Stein

Applicant(s)/Patent under  
Reexamination

KONDO, TAKAYUKI

Art Unit

2874

**SEARCHED**

Class	Subclass	Date	Examiner
385	14,24,49	4/25/2005	JDS <i>JDS</i>
398	141	4/25/2005	JDS <i>JDS</i>

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See attached EAST search History	4/25/2005	JDS <i>JDS</i>
IEEE and INSPEC: substrate, tile, transmitter, receiver, emitter, detector, mux, demux, multiplex, waveguide, display,	4/25/2005	JDS <i>JDS</i>